

FORM PTO-1449				Atty. Docket No.	Appln. No.		
<u>LIST OF DOCUMENTS CITED BY APPLICANT</u>				XA-9339C	10/614,242		
				Applicant			
				Yuichi OKUDA et al.			
VTC: D. Nguyen Primary Examiner				Filing Date HEREWITH	Group 2818		
U. S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
VN	AA	6,194,932	2/27/01	Takemae et al.	327	158	—
VN	AB	6,457,688	12/00	Tamura et al.	375	348	—
VN	AC	6,069,508	5/30/00	Takai	327	61	—
VN	AD	6,172,537	1/01	Kanou et al.	327	99	—
VN	AE	5,754,838	5/19/98	Shibata et al.	395	559	—
VN	AF	5,953,284	9/14/99	Baker et al.	365	233	—
VN	AG	6,166,990	12/26/00	Ooishi et al.	365	233	—
VN	AH	6,222,406	4/01	Noda et al.	327	269	—
AN	AI	6,081,142	6/27/00	Douchi et al.	327	158	—
VN	AJ	5,936,441	8/10/99	Kurita	327	141	—
VN	AK	5,926,053	7/20/99	McDermott et al.	327	298	—
FOREIGN PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Country	Class	Sub-class	Translation
VN	AL	2000-188540	7/00	Japan	—	—	cited by Examiner
VN	AM	2000-124796	4/00	Japan	—	—	cited by Examiner
VN	AN	2000-183730	6/00	Japan	—	—	cited by Examiner
VN	AO	2-90666	3/30/90	Japan	VTC: D. Nguyen Primary E.	—	Abstract
VN	AP	11-55145	2/26/99	Japan	—	—	Abstract
VN	AQ	10-171774	6/26/98	Japan	—	—	Abstract
OTHER (including author, title, date, pertinent pages, etc.)							
VN	AR	Johnson et al., "A Variable Delay Line PLL for CPU-Coprocessor Synchronization", IEEE Journal of Solid-State Circuits, Vol. 23, No. 5, pp. 1218-1223, October 1998					
Examiner V. Nguyen				Date Considered 6/25/09			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							

VTC: D. Nguyen  
Primary Examiner

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				Filing Date	Group		
				HEREWITH	2818		
U. S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
VN	AA*	6,191,632	12/20/01	Iwata	327	295	
VN	AB*	5,883,534	3/16/99	Kondoh et al.	327	156	
VN	AC*	6,377,511	4/23/02	Okuda et al.	365	233	
VN	AD*	6,373,303	4/16/02	Akita	327	156	
VN	AE*	5,619,148	4/8/97	Guo	327	3	
VN	AF*	2001/0021953	09/13/01	Nakashima	710	5	
VN	AG*	2002/0008589	01/24/02	Lanoman et al.	331	34	
VN	AH*	2002/0033737	3/21/02	Staszewski et al.	331	17	
VN	AI*	6,452,859	09/17/02	Shimano et al.	365	230.06	
VN	AJ*	6,172,537	01/09/01	Kanou et al.	327	99	
VN	AK*	6,518,813	02/11/03	Usui	327	291	
FOREIGN PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Country	Class	Sub-class	Translation
AL							
AM							
AN							
AO							
AP							
AQ							
OTHER (including author, title, date, pertinent pages, etc.)							
AR							
Examiner				Date Considered			
V. Nguyen				6/25/04			
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FORM PTO-1449			Atty. Docket No.	Appln. No.
<u>LIST OF DOCUMENTS CITED BY APPLICANT</u>			XA-9339C	10/614,292
			Applicant	
			Yuichi OKUDA et al.	
			Filing Date HEREWITH	Group 2818

## U. S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
W	AA+	6,463,008	10/08/02	Okuda et al.	365	233	
W	AB+	2001/0017558	08/30/01	Hanzawa et al.	327	165	
W	AC+	6,336,901	01/08/02	Itonaga et al.	600	499	
W	AD+	6,281,725	08/28/01	Hanzawa et al.	327	152	
W	AE+	6,269,051	07/31/01	Funaba et al.	365	233	
W	AF+	6,222,792	04/24/01	Hanzawa et al.	365	233	
	AG+						
	AH+						
	AI+						
	AJ+						
	AK+						

## FOREIGN PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Country	Class	Sub-class	Translation
	AL						
	AM						
	AN						
	AO						
	AP						
	AQ						

## OTHER (including author, title, date, pertinent pages, etc.)

AR	
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Examiner	Date Considered
V. Nguyen	6/25/09
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